

Day 1 - Monday 7th April 2025

18:00 Pre-conference networking drinks reception

Day 2 - Tuesday 8th April 2025

08:00 Registration and welcome refreshments

08:50 Housekeeping by Chris Meadows and Tim Bettles - Conference Chairs

Expanding the emission envelope

09:00 Expanding the Spectral Range of GaN-based SLEDs

Presented by Marco Malinverni - Exalos

09:15 Perfecting GaN VCSEL Production Process

Presented by Tetsuya Takeuchi - Meijo University

09:30 Connected Metrology for Growth and Characterization of InP and GaAs Laser Structures – from Epi to Etch

Presented by Iris Claussen - LayTec AG

09:45 Germanium as an Enabler for Large Volume Production in PV and Photonics

Presented by Ivan Zyulkov - Umicore

10:00 InP NIR VCSELs from 1.3 μm to beyond 2 μm for Single Mode and Multi Mode Applications

Presented by Christian Neumeyr - Vertilas

10:15 Ultraviolet to Infrared in a Single Spectrum

Presented by Yves Lacroix - YSystems Ltd

10:30 The Power of Pseudomorphic Nitrides

Presented by Leo Schowalter - Lit Thinking

10:45 Morning Break

GaN: Going beyond fast charging

11:25 Achieving Avalanche in GaN-on-silicon Diodes

Presented by Farid Medjdoub - University of Lille

11:40 Characterizing GaN: Challenges and Advances in Next-Generation Semiconductor Metrology

Presented by Áron Pekker - Semilab

11:55 X-ray Metrology Solutions for Compound Semiconductors from Labs to Fabs.

Presented by Assunta Vigliante - Rigaku

12:10 AIXTRON Leading Epitaxy Solutions for High Volume Manufacturing of GaN-based Power Devices

Presented by Dr. Nicolas Muesgens - Aixtron

12:25 Improving GaN Defect Analysis and Characterization with Novel Electron Microscopy Workflow

Presented by Antonio Mani - Thermo Fisher Scientific

12:40 GaN's Takeover: The Next Big Leap in Power Electronics

Presented by Ezgi Dogmus - Yole Group

12:55 Lunch Break

14:25 Harnessing the Underestimated Potential of GaN in the Digitalization Revolution: A Catalyst for Unforeseen Innovation in Energy Efficiency

Presented by Roberto Crisafulli - STMicroelectronics

14:40 Epitaxial GaN Growth using MBE for the Development of Next-Generation Devices

Presented by Romain Bruder - Riber

14:55 VECTOR: Advancing SEM Metrology with Automation and Versatility

Presented by Amanda Wscieklica - Raith

15:10 Driving Adoption of GaN for Power Electronics via 300mm Technology

Presented by Rudy Parekh - Veeco

15:25 Advancement in X-Ray Metrology for High Volume Manufacturing of GaN Based Power Devices

Presented by Qian Zheng - Bruker

15:40 Afternoon Break

Maintaining momentum for the microLED

16:20 Perfecting the Polychromatic Pixel

Presented by Michelle Chen - Q-Pixel Inc

16:35 MicroSolid Printing: Redefining the Future of MicroLED Displays

Presented by Reza Chaji - VueReal

16:50 Leveraging NIL for μLED Lens Packaging

Presented by Thomas Achleitner - EV Group

17:05 The Future of MicroLED Displays: Which Applications Are Leading in 2025?

Presented by Raphaël Mermet-Lyaudoz - Yole Group

17:20 Pioneering Mass Production and Commercialisation of MicroLED Microdisplays for AR

Presented by Kunal Kashyap - Porotech

- 17:35

Revolutionising microLED Displays with Nanowires

Presented by Pierre Tchoufian - Aledia
- 17:50

Closing Remarks
- 18:00

Networking Drinks / Dinner Reception

Day 3 - Wednesday 9th April 2025

- 08:00Registration and welcome refreshments
- 08:50Housekeeping by Chris Meadows and Tim Bettles - Conference Chairs

Optimising opportunities for SiC success

- 09:0020 Years of SiC Innovation Leadership: Trench-Assisted Planar Gate Technology
Presented by Llewellyn Vaughan-Edmunds - Navitas
- 09:15Solving Challenges in Compound Semiconductors: An Equipment Supplier’s Perspective
Presented by David Britz - Applied Materials
- 09:30Building the World’s Most Cost-efficient SiC Fab
Presented by Peter Friedrichs - Infineon
- 09:45Integrated Metal Etch and Photoresist Strip Solution for SiC Manufacturing
Presented by Bernhard Hammerl - Siconnex Customized Solutions GmbH
- 10:00High Sensitivity & Throughput Defect Inspection Technologies for SiC and GaN Power Technologies
Presented by Mike Rosa - Onto Innovation
- 10:15SCREEN’s Sustainable Cost-of-Ownership (CoO) Portfolio for Wafer Inspection and Thickness Measurement Tools and HVM experience
Presented by Alessandro Rossi - SCREEN SPE

10:30Morning Break

- 11:10Artificial Intelligence for SiC Yield Optimization
Presented by Marius Fischer - Nanotronics
- 11:25PVA TePla Metrology Solutions for Compound Semiconductors
Presented by Ivan Orlov - PVA TePla AG, and Markus Stöhr - PVA TePla AG
- 11:40How Artificial Intelligence Heralds the New Era of Wafering
Presented by Malte Mueller - Lapmaster Wolters
- 11:55Crystal Orientation for Optimizing Quality and Yield throughout the Process Chain
Presented by Andrey Zameshin - Malvern Panalytical
- 12:10How to save process cost in your SiC/GaN production using best in class power supplies?
Presented by Yannick Schneider - TRUMPF

12:25Lunch Break

Ultra-wide bandgap materials: The ultimate devices

Sponsored by Precision Fabricators

- 13:55Prospects of (ultra) Wide Bandgap Oxide ICs
Presented by Xiaohang Li - KAUST
- 14:10A Solution to Doping AlN Enabling a New Era of Nitride Semiconductors
Presented by Alan Doolittle - Georgia Institute of Technology
- 14:25Electric Field Engineering to Unlock the Potential of Gallium Oxide Power Devices
Presented by Nolan Hendricks - AFRL (Air Force Research Laboratory)
- 14:40Efficient Diameter Enlargement of Bulk AlN
Presented by Carsten Hartmann - Leibniz-Institut für Kristallzüchtung (IKZ)
- 14:55The promise of cubic Boron Nitride (c-BN)
Presented by Siddha Pimputkar - Lehigh University
- 15:10Closing Remarks

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